PAV200

200 mm Semi-automated Vacuum Probe System

Overview

Cascade PAV200 probe system from FormFactor is the ideal solution for automatic testing of wafers and substrates up to 200 mm in a high vacuum environment $< 1 \times 10^{-4}$ mbar. It supports a wide temperature range from -60°C to 300°C.

It supports a wide range of applications, including DC and RF measurements, MEMS and opto-engineering tests. The probe platen is designed to mount probe cards or up to eight vacuum-type positioners on magnetic feet. A high-resolution video microscope with 50 mm x 50 mm travel range is mounted either on a microscope mount with swivel or on a microscope bridge for vibrationsensitive test applications and additional test instruments.



The PAV200 is equipped with a stable vibration isolating frame. The chuck and the motorized chuck stage with 200 mm x 200 mm X-Y travel, theta and Z-axis are located inside the high-vacuum chamber. Up to eight vacuum-type positioners can be easily operated from outside of the chamber via vacuum-tight mechanical feedthrough drives and cardan shafts. For the use under vacuum conditions, specially-designed thermal chucks with electrical and cooling line bulk-feedthroughs are available.

> Features / Benefits

Flexibility	Different substrate carriers for wafers up to 200 mm or single dies
	 Upstream pressure, downstream pressure or medium vacuum regulation
	 Velox[™] probe station control software
	 Wide range of measurements (I-V, C-V, two-port, multi-port and differential RF)
	• RF tests supported by a wide range of probes and calibration tools, such as calibration substrates and WinCal XE™ calibration software
	 Accessories available, such as Black Bodies and optical motion analysis tools
Stability	High accuracy, ideal for small structures
	 Highly stable mechanics with a stable vibration isolation table
Ease of use	Simple, straightforward design for easy and ergonomic operation
	 Quick and ergonomic change of the DUT through front door
Automation	Pressure control: up-stream, down-stream, high-precision capacitance vacuum gauges
	Bridge with rails for programmable movement of mounted instruments
High measurement	Automatic control of chuck for fast step-and-repeat testing of the entire wafer throughput



> Applications

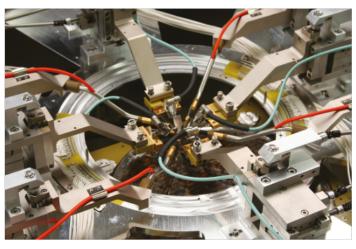
MEMS Acceleration sensors

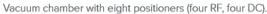
RF MEMS switches Micro-bolometers Gyro sensors Gas sensors

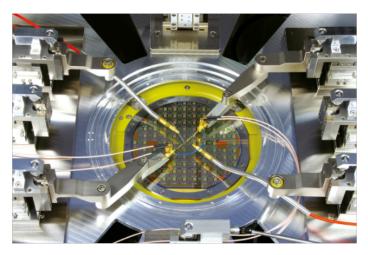
Pressure sensors

MOEMS Micro-mirrors

Optical switches







Vacuum chamber with four DC positioners.

> Vacuum Probecard

Vacuum Probecard

Customer electronics on board possible

Easy-to-use probecard holder for fast change of probe card

Needle ring for up to 120 needles

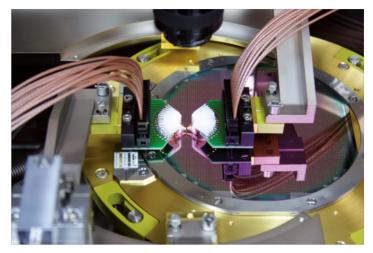
Coax and/or twisted-pair cabling

Pseudo Kelvin cabling – junction point at probecard holder

Alternatively, DC ProbeWedges™ can be used



Vaccum probe card.



Two DC ProbeWedges on positioners.



> Handling







Probe positioning.

> Integration of Third-Party MEMS Test Tools

Polytec MSA-500 For out-of-plane and in-plane motion analysis and optional topology measurements

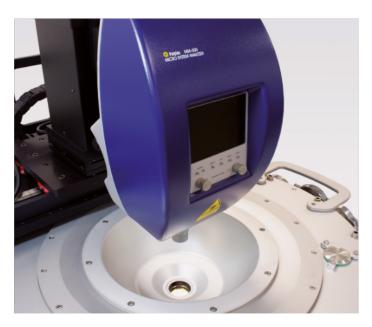
Seamless integration of both systems by Cascade Microtech and Polytec Communication Tool

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Black bodies For controlled exposure with infrared radiation for microbolometer testing

Cavity or surface type can be adopted

Aperture, filter and shutter functions are optionally available



Polytec MSA-500 over topside viewport for mechanical motion analysis.



PAV200 with Black Body for microbolometer testing.

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Corporate Headquarters 7005 Southfront Road Livermore, CA 94551 Phone: 925-290-4000 www.formfactor.com

